

AON7426-VB Datasheet N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (Ω) Typ.	I _D (A)	Q _g (Typ.)		
30	0.004 at $V_{GS} = 4.5 \text{ V}$	60	33.5 nC		
30	0.005 at V _{GS} = 2.5 V	50	33.3110		

FEATURES

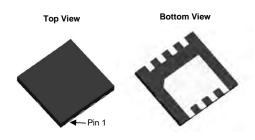
Halogen-free According to IEC 61249-2-21 Definition



- TrenchFET® Power MOSFET
- 100 % $\rm R_{\rm g}$ and UIS Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

- Motor Control
- Industrial
- Load Switch
- ORing



Continuous Drain Current (T_J = 150 °C)

Continuous Source-Drain Diode Current

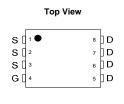
Pulsed Drain Current (t = 300 μs)

Single Pulse Avalanche Current

Single Pulse Avalanche Energy

Maximum Power Dissipation

DFN 3x3 EP



T_C = 25 °C

T_C = 70 °C

T_A = 25 °C

 $T_{\Delta} = 70 \, ^{\circ}C$

T_C = 25 °C

T_A = 25 °C

L = 0.1 mH

T_C = 25 °C

T_C = 70 °C

T_A = 25 °C T_A = 70 °C Symbol

 V_{DS}

 V_{GS}

 I_D

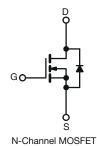
 I_{DM}

 I_S

I_{AS}

EAS

 P_D



20

52

33

3.7^{b, c}

2.4^{b, c}

ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C, unless otherwise noted) Limit Unit 30 ٧ ± 20 60^{a, e} 40^{a, e} 22^{b, c} 15^{b, c} 150 35 3.3^{b, c} 20

Operating Junction and Storage Temperature Range		T _J , T _{stg}	-	- 55 to 150	
Soldering Recommendations (Peak Temperature)				260	
			•		•
THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	24	33	°C/W
Maximum Junction-to-Case (Drain)	Steady State	Renic	1.9	2.4	

Notes:

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.

Parameter

Drain-Source Voltage

Gate-Source Voltage

d. Maximum under steady state conditions is 90 °C/W.

e. Calculated based on maximum junction temperature. Package limitation current is 80 A.

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mJ

W



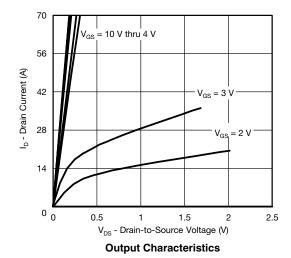
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050A		30		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	0.5		1.5	٧	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Wallana Busin Oamant	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μА	
Zero Gate Voltage Drain Current		V_{DS} = 30 V, V_{GS} = 0 V, T_J = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
D : 0	Б	$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		0.0040		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 2.5 \text{ V}, I_D = 7 \text{ A}$		0.0050			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A		65		S	
Dynamic ^b				ı		<u> </u>	
Input Capacitance	C _{iss}			6000		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		406			
Reverse Transfer Capacitance	C _{rss}			360			
Total Gate Charge	Q _g —	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		68	102	nC	
				33.5	51		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		7.7			
Gate-Drain Charge	Q_{gd}			13.8			
Gate Resistance	R_{g}	f = 1 MHz	0.3	0.7	1.4	Ω	
Turn-On Delay Time	t _{d(on)}			24	45		
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		24	45		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 10 A, V_{GEN} = 4.5 V, R_g = 1 Ω		32	60		
Fall Time	t _f			12	24	1	
Turn-On Delay Time	t _{d(on)}			14	28	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		13	26		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 10$ A, V_{GEN} = 10 V, R_g = 1 Ω		33	60		
Fall Time	t _f			8	16		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C		35		А	
Pulse Diode Forward Current	I _{SM}			70			
Body Diode Voltage	V _{SD}	I _S = 3 A, V _{GS} = 0 V		0.7	1.1	٧	
Body Diode Reverse Recovery Time	t _{rr}			21	40	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 10 A dl/dt 100 A/v- T 05 00		10	20	nC	
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		9			
Reverse Recovery Rise Time t _b				12		ns	

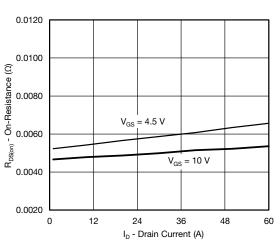
Notes:

- a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 % b. Guaranteed by design, not subject to production testing.

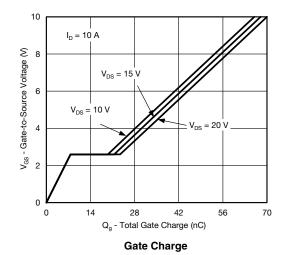
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

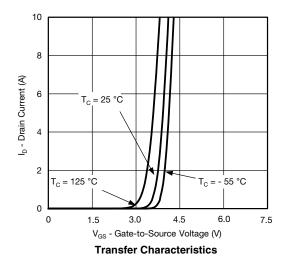


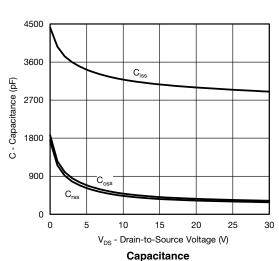


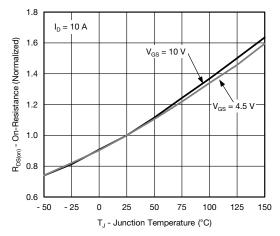


On-Resistance vs. Drain Current and Gate Voltage



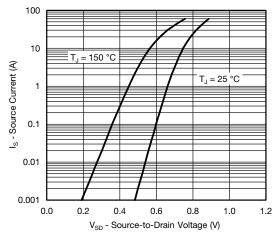




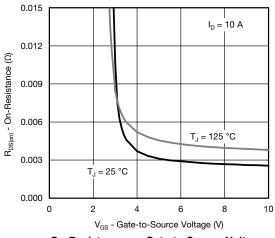


On-Resistance vs. Junction Temperature

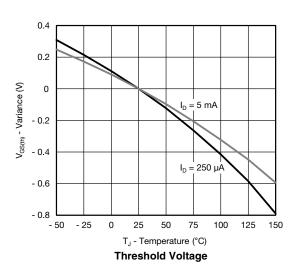


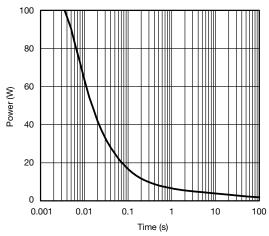


Source-Drain Diode Forward Voltage

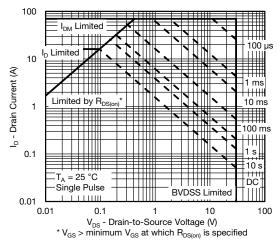


On-Resistance vs. Gate-to-Source Voltage



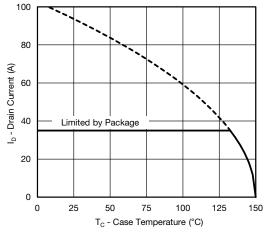


Single Pulse Power, Junction-to-Ambient

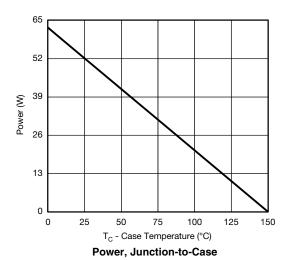


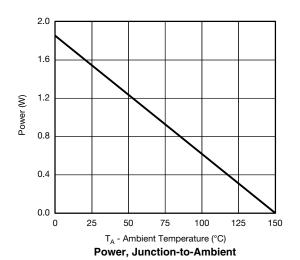
Safe Operating Area, Junction-to-Ambient





Current Derating*

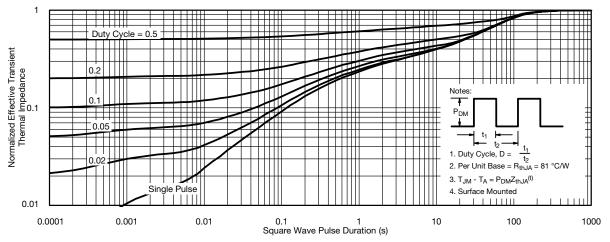




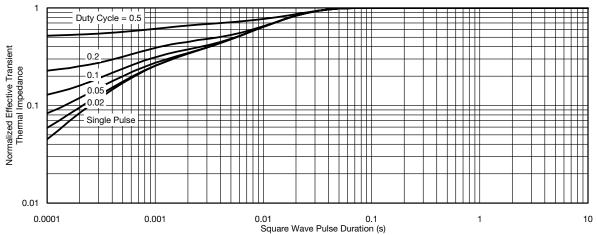
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^{*} The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



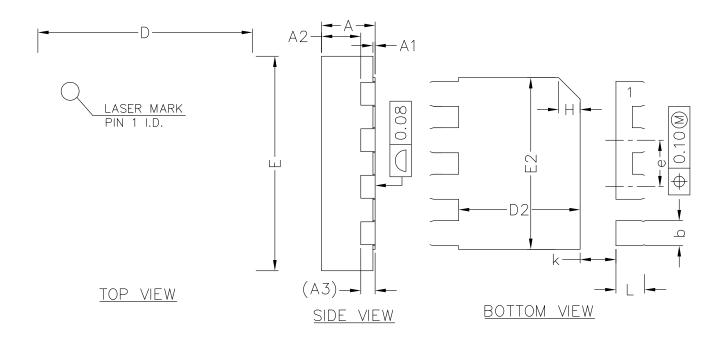


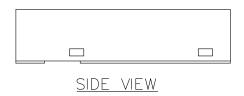
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case







COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
Α	0.70	0.75	0.80
A1	0.00	0.02	0.05
A2	0.50	0.55	0.60
А3	0.20REF		
Ь	0.30	0.35	0.40
D	2.90	3.00	3.10
E	2.90	3.00	3.10
D2	1.60	1.70	1.80
E2	2.30	2.40	2.50
е	0.55	0.65	0.75
K	0.40	0.50	0.60
L	0.35	0.40	0.45



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